

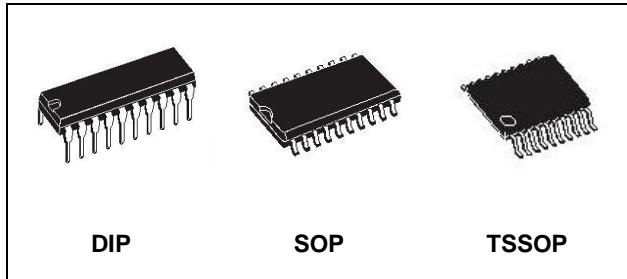


Beijing Relitech Co., LTD.

**RD74HC245**

## OCTAL BUS TRANSCEIVER WITH 3 STATE OUTPUTS (NON INVERTED)

Datasheet- production data



DIP

SOP

TSSOP

### Features

- HIGH SPEED:  
 $t_{PD} = 10\text{ns}$  (TYP.) at  $V_{cc} = 6\text{V}$
- LOW POWER DISSIPATION:  
 $I_{cc} = 4\mu\text{A}$  (MAX.) at  $T_A=25^\circ\text{C}$
- HIGH NOISE IMMUNITY:  
 $V_{NIH} = V_{NIL} = 28\%$   $V_{cc}$ (MIN.)
- SYMMETRICAL OUTPUT IMPEDANCE:  
 $|I_{OH}| = I_{OL} = 6\text{mA}$  (MIN.)
- BALANCED PROPAGATION DELAYS:  
 $t_{PLH} \cong t_{PHL}$
- WIDE OPERATING VOLTAGE RANGE:  
 $V_{cc}$ (OPR.) = 2V to 6V

### Description

The RD74HC245 is an advanced high-speed CMOS OCTAL BUS TRANSCEIVER (3-STATE) fabricated with silicon gate CMOS technology.

This IC is intended for two-way asynchronous communication between data buses, and the direction of data transmission is determined by DIR input. The enable input  $\overline{G}$  can be used to disable the device so that the buses are effectively isolated.

All inputs are equipped with protection circuits against static discharge and transient excess voltage.

All floating bus terminals during High Z State must be held HIGH or LOW.

**Table 1. Device summary**

PART NUMBER	PACKAGE
RD74HC245BDI	DIP20
RD74HC245BSO	SOP20
RD74HC245BTS	TSSOP20



## 1 Pin information

Figure 1. Pin connection and IEC logic symbols

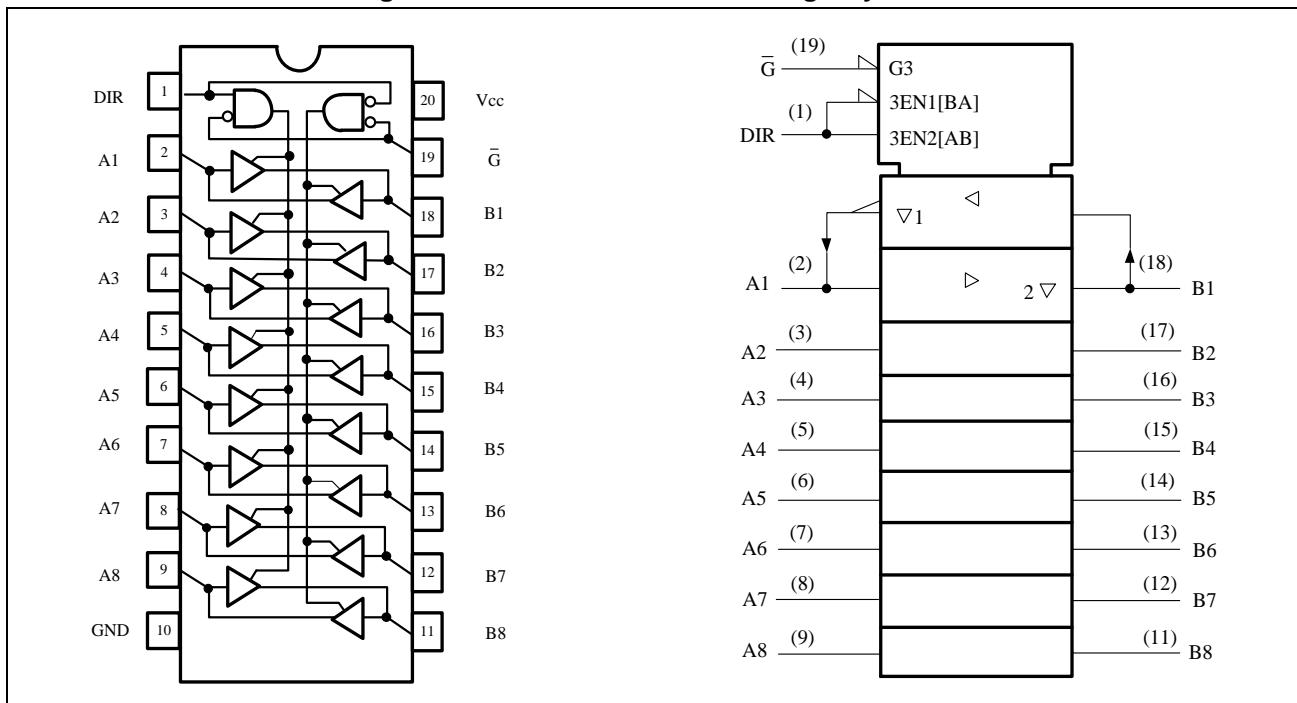


Table 2. Pin description

Pin No	Symbol	Name and function
1	DIR	Directional Control
2, 3, 4, 5, 6, 7, 8, 9	A1 to A8	Data Inputs/Outputs
18, 17, 16, 15, 14, 13, 12, 11	B1 to B8	Data Inputs/Outputs
19	$\bar{G}$	Output Enable Input
10	GND	Ground (0V)
20	V <sub>CC</sub>	Positive Supply Voltage

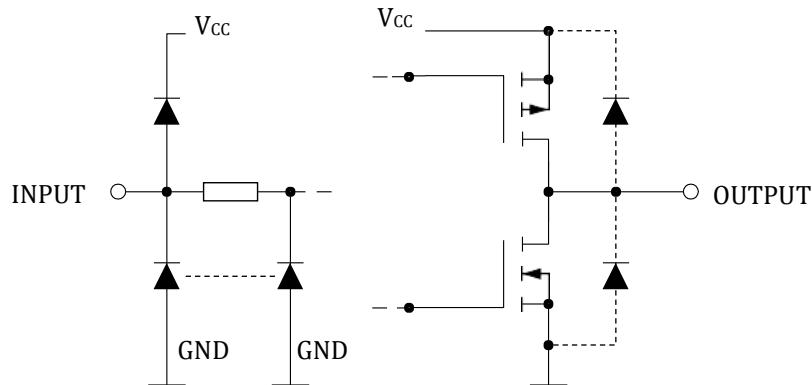
## 2 Functional description

Table 3. Truth table

INPUTS		FUNCTION		OUTPUT
$\bar{G}$	DIR	A BUS	B BUS	$Y_n$
L	L	OUTPUT	INPUT	$A = B$
L	H	INPUT	OUTPUT	$B = A$
H	X	Z	Z	Z

X = Don't care

Z = High impedance

**Figure 2. Input and output equivalent circuit**

### 3 Electrical characteristics

**Table 4. Absolute maximum ratings**

Symbol	Parameter	Value	Unit
V <sub>CC</sub>	Supply Voltage	-0.5 to + 7.0	V
V <sub>I</sub>	DC Input Voltage	-0.5 to V <sub>CC</sub> + 0.5	V
V <sub>O</sub>	DC Output Voltage	-0.5 to V <sub>CC</sub> + 0.5	V
I <sub>IK</sub>	DC Input Diode Current	± 20	mA
I <sub>ok</sub>	DC Output Diode Current	± 20	mA
I <sub>O</sub>	DC Output Current	± 35	mA
I <sub>CC</sub> or I <sub>GND</sub>	DC V <sub>CC</sub> or Ground Current	± 70	mA
P <sub>D</sub>	Power Dissipation	500 (*)	mW
T <sub>stg</sub>	Storage Temperature	-65 to + 150	°C
T <sub>L</sub>	Lead Temperature (10 sec)	300	°C

Absolute Maximum Ratings are those values beyond which damage to the device may occur. Functional operation under these conditions is not implied

(\*) 500mW at 65 °C; derate to 300mW by 10mW/°C from 65°C to 85°C

**Table 5. Recommended operating conditions**

Symbol	Parameter	Value	Unit
V <sub>CC</sub>	Supply Voltage	2 to 6	V
V <sub>I</sub>	Input Voltage	0 to V <sub>CC</sub>	V
V <sub>O</sub>	Output Voltage	0 to V <sub>CC</sub>	V
T <sub>op</sub>	Operating Temperature	-40 to +85	°C
t <sub>r</sub> , t <sub>f</sub>	Input Rise and Fall Time	V <sub>CC</sub> = 2.0V	0 to 1000
		V <sub>CC</sub> = 4.5V	0 to 500
		V <sub>CC</sub> = 6.0V	0 to 400
			ns

**Table 6. DC specifications**

Symbol	Parameter	Test Condition		Value					Unit	
		V <sub>CC</sub> (V)		T <sub>A</sub> = 25 °C			-40 to 85°C			
				Min	Typ	Max	Min	Max		
V <sub>IH</sub>	High Level Input Voltage	2.0		1.5			1.5		V	
		4.5		3.15			3.15			
		6.0		4.2			4.2			
V <sub>IL</sub>	Low Level Input Voltage	2.0				0.5		0.5	V	
		4.5				1.35		1.35		
		6.0				1.8		1.8		
V <sub>OH</sub>	High Level Output Voltage	2.0	I <sub>O</sub> =-20μA	1.9	2.0		1.9		V	
		4.5	I <sub>O</sub> =-20μA	4.4	4.5		4.4			
		6.0	I <sub>O</sub> =-20μA	5.9	6.0		5.9			
		4.5	I <sub>O</sub> =-6.0 mA	4.18	4.31		4.13			
		6.0	I <sub>O</sub> =-7.8 mA	5.68	5.8		5.63			
V <sub>OL</sub>	Low Level Output Voltage	2.0	I <sub>O</sub> =20 μA		0.0	0.1		0.1	V	
		4.5	I <sub>O</sub> =20 μA		0.0	0.1		0.1		
		6.0	I <sub>O</sub> =20 μA		0.0	0.1		0.1		
		4.5	I <sub>O</sub> =6.0 mA		0.17	0.26		0.33		
		6.0	I <sub>O</sub> =7.8 mA		0.18	0.26		0.33		
I <sub>I</sub>	Input Leakage Current	6.0	V <sub>I</sub> = V <sub>CC</sub> or GND			±0.1		±1	μA	
I <sub>OZ</sub>	High Impedance Output Leakage Current	6.0	V <sub>I</sub> = V <sub>IH</sub> or V <sub>IL</sub> V <sub>O</sub> = V <sub>CC</sub> or GND			±0.5		±5	μA	
I <sub>CC</sub>	Quiescent Supply Current	6.0	V <sub>I</sub> = V <sub>CC</sub> or GND			4		40	μA	



**Table 7. AC electrical characteristics ( $C_L = 50\text{pF}$ , Input  $t_r = t_f = 6\text{ns}$ )**

Symbol	Parameter	Test Condition			Value					Unit	
		$V_{CC}$ (V)	$C_L$ (pF)		$T_A = 25^\circ\text{C}$			$-40 \text{ to } 85^\circ\text{C}$			
					Min	Typ	Max	Min	Max		
$t_{TLH}t_{THL}$	Output Transition Time	2.0	50			25	60		75	ns	
		4.5				7	12		19		
		6.0				6	10		13		
$t_{PLH}t_{PHL}$	Propagation Delay Time	2.0	50			33	90		115	ns	
		4.5				12	18		23		
		6.0				10	15		20		
		2.0	150			48	120		150	ns	
		4.5				16	24		30		
		6.0				14	20		26		
$t_{PZL}t_{PZH}$	High Impedance Output Enable Time	2.0	50	$R_L = 1\text{ k}\Omega$		48	150		190	ns	
		4.5				16	30		38		
		6.0				14	26		32		
		2.0	150	$R_L = 1\text{ k}\Omega$		63	180		225	ns	
		4.5				21	36		45		
		6.0				18	31		38		
$t_{PLZ}t_{PHZ}$	High Impedance Output Disable Time	2.0	50	$R_L = 1\text{ k}\Omega$		37	150		190	ns	
		4.5				17	30		38		
		6.0				15	26		32		

**Table 8. Capacitive characteristics**

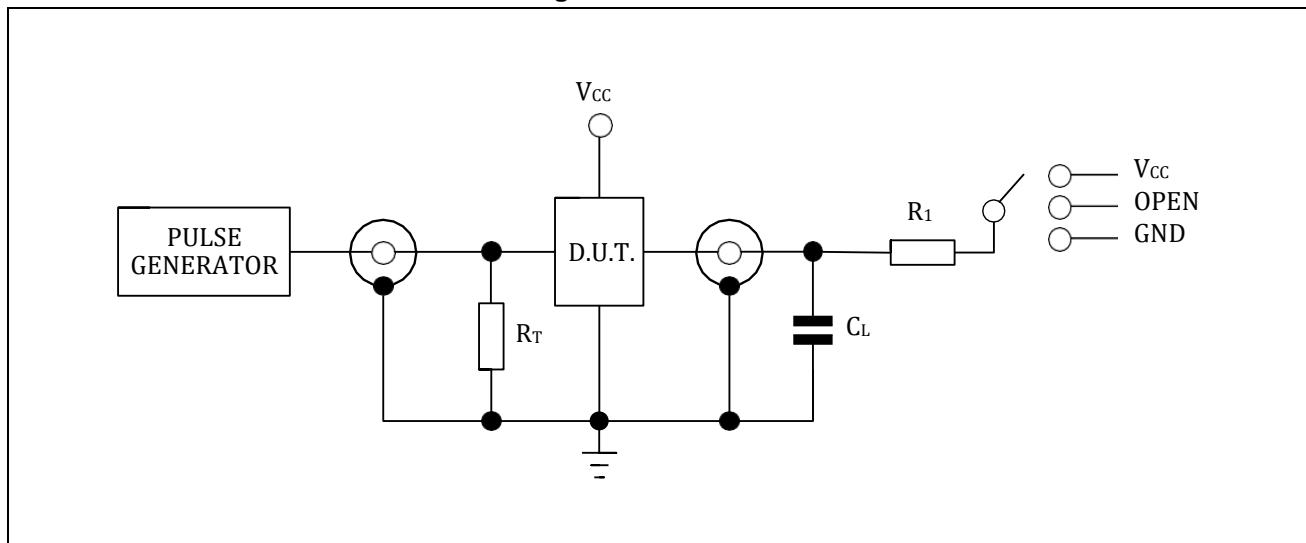
Symbol	Parameter	Test Condition			Value					Unit	
		$V_{CC}$ (V)			$T_A = 25^\circ\text{C}$			$-40 \text{ to } 85^\circ\text{C}$			
					Min	Typ	Max	Min	Max		
$C_{IN}$	Input Capacitance			DIR, $\bar{G}$		5	10		10	pF	
$C_{I/OUT}$	Output Capacitance			An, Bn		13				pF	
$C_{PD}$	Power Dissipation Capacitance <sup>(1)</sup>					39				pF	

1.  $C_{PD}$  is defined as the value of the IC's internal equivalent capacitance which is calculated from the operating current consumption without load. (Refer to test circuit). Average operating current can be obtained by the following equation:  
 $I_{CC(\text{opr})} = C_{PD} \times V_{CC} \times f_{IN} + I_{CC}/8$  (per circuit)



## 4 Test circuit

Figure 3. Test circuit



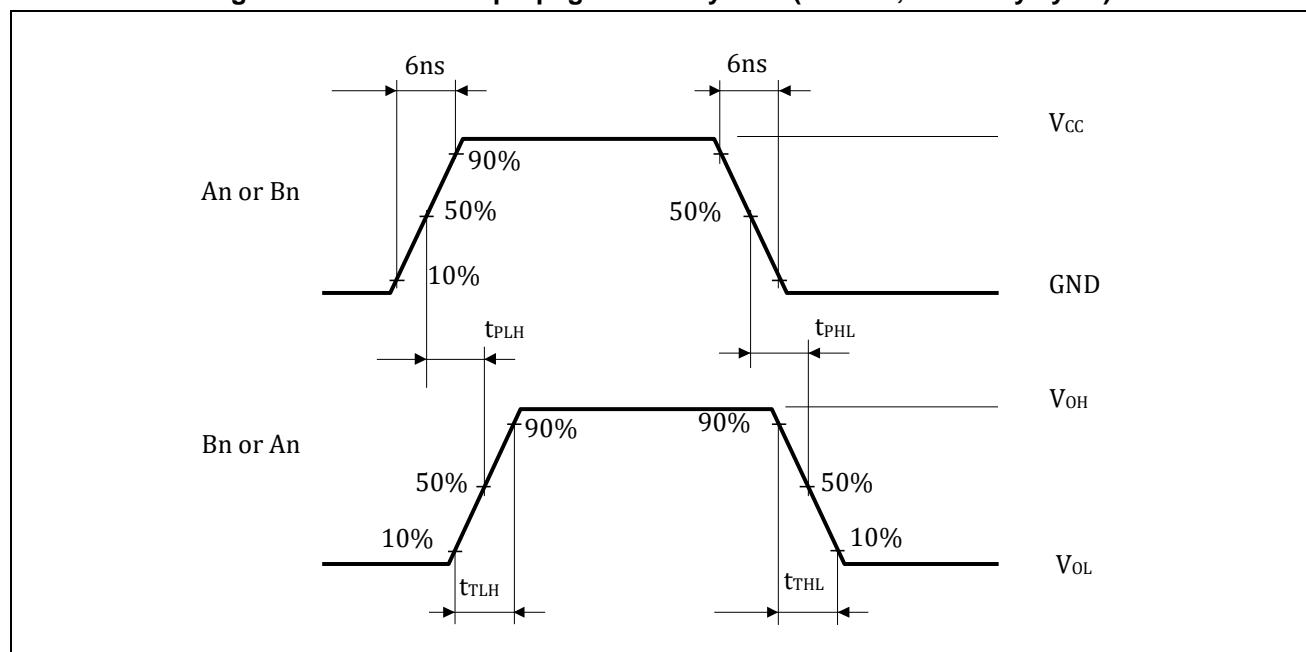
TEST	SWITCH
$t_{PLH}, t_{PHL}$	OPEN
$t_{PZL}, t_{PLZ}$	VCC
$t_{PZH}, t_{PHZ}$	GND

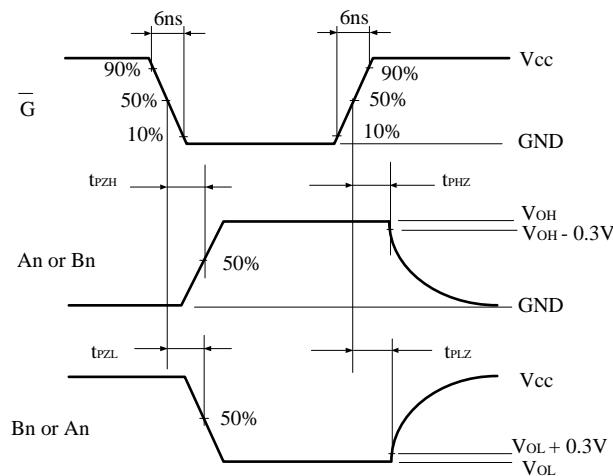
$R_T = Z_{OUT}$  of pulse generator (typically  $50\Omega$ )

$R_1 = 1K\Omega$  or equivalent

$C_L = 50pF/150pF$  or equivalent (includes jig and probe capacitance)

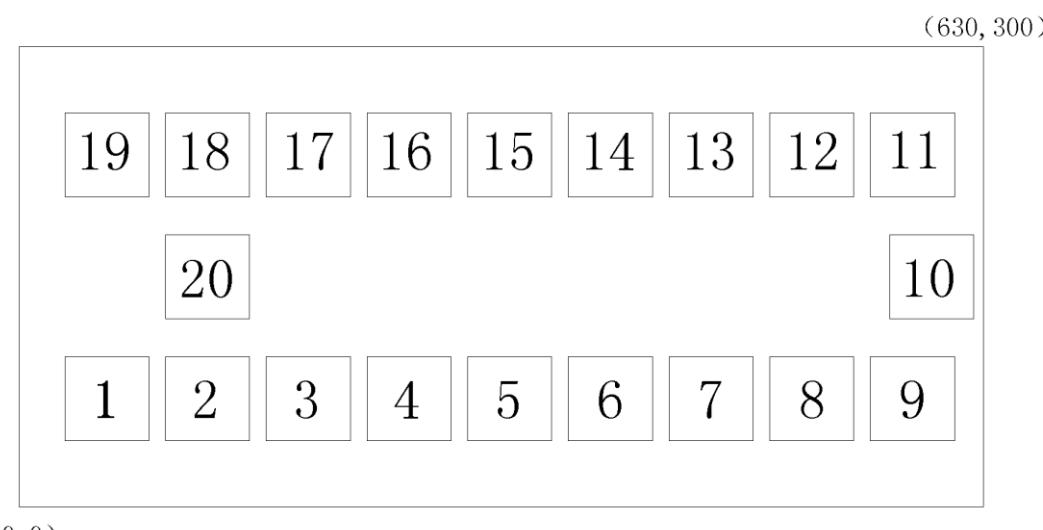
Figure 4. Waveform 1: propagation delay time ( $f=1MHz$ ; 50% duty cycle)



**Figure 5. Waveform 2: output enable and disable time (f=1MHz; 50% duty cycle)**

## 5 Die Information

Die Type	RD74HC245	Wafer Size	8 Inch
Die Size ( $\mu\text{m}$ )	X/Y: 630/300	Bond Area ( $\mu\text{m}$ )	X/Y: 55/55
Scribeline ( $\mu\text{m}$ )	60	Chip Thickness	
Metal	Front	Al+0.5%Cu	
	Back	Si	
	Top Metal Thickness	12000 $\text{\AA}$	



Pin No.	Pin Name	Coordinate		Pin No.	Pin Name	Coordinate	
		X	Y			X	Y
1	DIR	57.3	70.5	11	B8	583.7	229.5
2	A1	123.1	70.5		B7	517.9	229.5
3	A2	188.9	70.5		B6	452.1	229.5
4	A3	254.7	70.5		B5	386.3	229.5
5	A4	320.5	70.5		B4	320.5	229.5
6	A5	386.3	70.5		B3	254.7	229.5
7	A6	452.1	70.5		B2	188.9	229.5
8	A7	517.9	70.5		B1	123.1	229.5
9	A8	583.7	70.5		G	57.3	229.5
10	GND	596.35	150.0		V <sub>CC</sub>	123.1	150.0

## 6 Ordering information

Table 9. Device summary

Order code	Package	Packing
RD74HC245BDI	DIP20	Tape and reel
RD74HC245BSO	SOP20	
RD74HC245BTS	TSSOP20	
RD74HC245B		

## 7 Revision history

Table 10. Document revision history <sup>(1)</sup>

Date	Revision	Changes
18-Jan-2022	1	Initial release
12-Dec-2023	2	Added : Die information Revised document presentation, minor textual updates

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